

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/746,490	BENDAK ET AL.	
Examiner	Art Unit	

2664

John L. Shew

SEARCHED				
Class	Subclass	Date	Examiner	
370	350,370	5/16/2005	JS	
	395.5			
	401,466			
	467,503			
	505			
	509-517			
	527,529			
375	356-357	5/16/2005	JS	
	359,362			
	365,366			
	368			
714	775,776	5/16/2005	JS	
	789			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
370	510	5/16/2005	JS	
375	366	5/16/2005	JS	
714	789	5/16/2005	JS	

(INCLUDING SEARC	IN STRATEG) Y)
	DATE	EXMR
	•	
		İ
	_	-